







"MACRO meets NANO in Measurement for Diagnostics, Optimization and Control" Delft, The Netherlands on September 21-22,

2023

Closing and Awards Ceremony Dr. Zsolt János VIHAROS

Senior research fellow, Institute for Computer Science and Control

Vice Dean for Science of the John von Neumann University

President of the Hungarian Member Organisation (MO) of IMEKO

Chairperson, IMEKO TC10 on Measurement for Diagnostics, Optimization and Control



About IMEKO International Measurement Confederation

- TC1 Education and Training in Measurement and Instrumentation (established in: 1967)
- TC2 Photonics (established in 1962)
- TC3 Measurement of Force, Mass and Torque (1967-1998: Measurement of Force and Mass)
- TC4 Measurement of Electrical Quantities (established in 1984)
- TC5 Hardness Measurement (established in 1973)
- TC6 Digitalization (until 2020: Vocabulary Committee)
- TC7 Measurement Science (1975-1993: Measurement Theory)
- TC8 Traceability in Metrology (established in 1972)
- TC9 Flow Measurement (established in 1976)

- TC10 Measurement for Diagnostics, Optimization & Control (established in 1976)
- TC11 Measurement in Testing, Inspection and Certification
- TC12 Temperature and Thermal Measurements (established in 1979)
- TC13 Measurements in Biology and Medicine (established in 1980)
- TC14 Measurement of Geometrical Quantities (established in 1980)
- TC15 Experimental Mechanics (established in 1984)
- TC16 Pressure and Vacuum Measurement (established in 1986)
- TC17 Measurement in Robotics (established in 1987)

- TC18 Measurement of Human Functions (established in 1998)
- TC19 Environmental Measurements (established in 1999)
- TC20 Measurements of Energy and Related Quantities (1999 -2010: Measurement Techniques for the Construction Industry, 2010 - 2015: Energy Measurement)
- TC21 Mathematical Tools for Measurements (established in 2004)
- TC22 Vibration Measurement (established in 2005)
- TC23 Metrology in Food and Nutrition (established in 2006)
- TC24 Chemical Measurement (established in 2008)
- TC25 Quantum Measurement and Quantum Information (established in 2021)



19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control" INVITATION

The International Measurement Confederation IMEKO, Technical Committee 10 on Measurement for Diagnostics, Optimization and Control (https://www.imeko.org/index.php/tc10-homepage) kindly invites you to attend the

19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control"

Delft, The Netherlands on September 21-22, **2023**.

The Conference is a forum for advancing knowledge and exchange ideas on methods, principles, instruments, technologies and IT tools, standards, industrial applications, conformity assessment, quality management and measurement challenges on Diagnostics, Optimization and Control as well as their diffusion across the scientific community. Participants have an excellent opportunity to meet top specialists from industry and academia all over the world and to enhance their international cooperation. The programme will feature scientists and experts as leading keynote speakers for selected presentations on the conference's main topics.



IMEKO TC10 History (<u>19</u> Conferences + 17/23 World Congresses SZTAKI

HUNGARY

HUNGARY

POLAND FRANCE

GERMAN D. R.

UNITED KINGDOM SOVIET UNION

F. R. GERMANY CZECHOSLOVAKIA

USA

ITALY

JAPAN
AUSTRIA
CROATIA

BRAZIL

JAPAN

GERMANY

PORTUGAL

REPUBLIC of KOREA

CZECH REPUBLIC
UNITED KINGDOM

P. R. CHINA

IMEKO TC10 Events

TC 10 Conference2023	Delft T	he Neth	erlands	
<u>Name</u>	Year	<u>Place</u>	<u>Country</u>	
TC10 Conference 2022	2022	Warsaw	POLAND	
TC10 Conference 2020 (ONLINE)	2020	Dubrovnik	CROATIA	
TC10 Conference 2019	2019	Berlin	GERMANY	
TC10 Workshop on Technical Diagnostics 2017	2017	Budapest	HUNGARY	
TC10 Workshop on Technical Diagnostics 2016	2016	Milano	ITALY	1
TC10 Workshop on Technical Diagnostics 2014	2014	Warsaw	POLAND	7
TC10 Workshop 2013	2013	Florence	ITALY	<u>I</u>
TC10 Workshop 2010	2010	Krakow	POLAND	<u>></u>
TC10 International Workshop on Technical Diagnostics 2008	2008	Budapest	HUNGARY	X
TC10 Conference 2005	2005	Budapest	HUNGARY	XI
TC10 Symposium 2001	2001	Compiègne	FRANCE	X
TC10 Symposium 1999	1999	Wroclaw	POLAND	X
TC10 Workshop 1995	1995	Trondheim	NORWAY	X
TC10 Symposium 1992	1992	Dresden	GERMANY	
TC10 Workshop 1991	1991	Warsaw	POLAND	XV
TC10 Symposium 1990	1990	Helsinki	FINLAND	XVII
TC10 Conference 1989	1989	Prague	CZECHOSLOVAKIA	XVIII
TC10 Workshop 1988	1988	Budapest	HUNGARY	XIX IM
TC10 Conference 1987	1987	Paderborn	F. R. GERMANY	XX IMI
TC10 Conference 1986	1986	Dubrovnik	YUGOSLAVIA	XXII
TC10 Conference 1981	1981	London	UNITED KINGDOM	XXII
2-day Meeting of TC10 1980	1980	Nienwagen	THE NETHERLANDS	XXII
TC10 Conference 1979	1979	Karlovy Vary	CZECHOSLOVAKIA	XXIV



SZTAKI

19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control"

SPONSORS



Seeing beyond













Measurement for Diagnostics, Optimization and Con

19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control"

INVITED KEYNOTE LECTURERS

Keynote speaker

Dr. Richard Quintanilha

Optical System Engineer, Corporate Research & Technology Carl Zeiss AG, Carl-Zeiss-Straße 22, 73447 Oberkochen, Germany

Dr. Richard Quintanilha received his PhD degree in physics from the University of Grenoble, France in 2005, for his research in spectroscopic scatterometry carried out within Crolles 2 Alliance and CEA\LETI. He joined the National Institute for Standard and Technology (NIST), The USA, Gaithersburg, MD in 2006 where he worked in the development and research of an UV transmission microscope and a deep UV reflective microscope for standards and metrology mainly dedicated to microelectronic industry process control (CD measurement, defectivity, etc.). He joined ASML Research Netherlands B.V. Veldhoven, The Netherlands in 2010 in the Sensors, Metrology and Computational Modeling (SMC) group where his work was focused on metrology for future technology nodes. He joined in 2018 ZEISS-SMT in Oberkochen, Germany. His work was focused on metrology for EUV mirror characterization. Since 2022, He works in ZEISS AG Corporate Research and Technology as an Optical System Engineer.

Lecture: Carl ZEISS and Metrologies

General introduction to ZEISS group and its different Segments with a special place for the Semiconductor Manufacturing Technology Segment. The talk will focus on manufacturing and associated metrology requirements challenges through some examples coming from different segments of the company. A more detail presentation of the DUV-EUV optics manufacturing and metrology is discussed.







19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control"

Keynote speaker

Poul Erik Hansen

Principal scientist at Principal scientist, Danich National Metrology Institute, Kogle Alle 5, DK-2970 Hørsholm, Denmark

Poul-Erik Hansen got his Ph.D. in Physics in 1998 at Aalborg University, Denmark. Since 2006 he has worked as a research scientist at Danish Fundamental Metrology in the field of surface metrology, scatterometry as well as ellipsometry and confocal microscopy. He also has an expertise in advanced mathematical modeling of the light matter interaction. Poul-Erik is a leader of several Danish projects on optical Metrology and scattering of nanosized objects and has authored more than 60 papers in international peer reviewed journals.

Lecture: Traceability and uncertainty in optical measurements

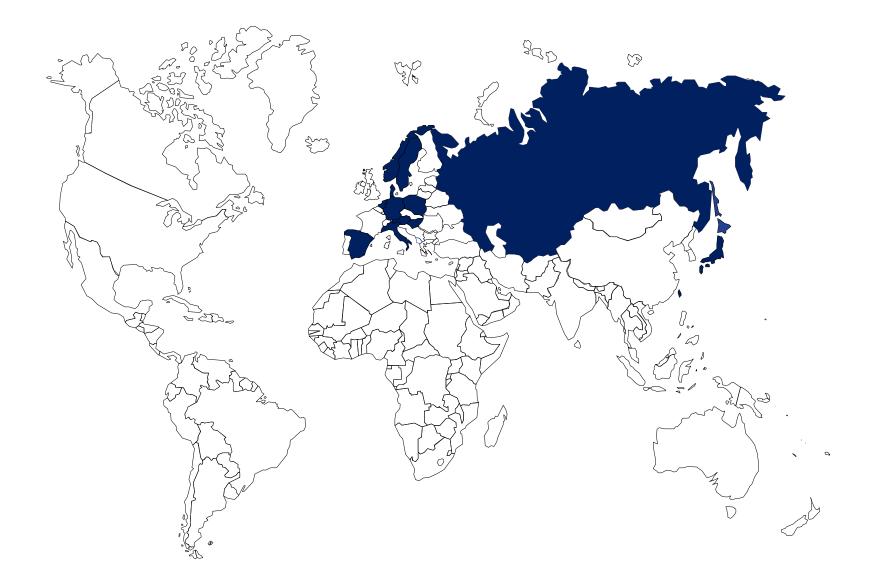
The talk is meant to provide users of metrology and the general public with a simple yet comprehensive overview on the subject. It targets those who are not familiar with the topic and who require an introduction, as well as those who are involved in metrology at various levels but who want to know more about the subject or simply gain specific information. Metrology is the science of measurements and covers three main activities. 1) The definition of internationally accepted units of measurement, 2) The realization of units of measurement by scientific methods and 3) The establishment of traceability chains by determining and documenting the value and accuracy of a measurement and disseminating that knowledge. This talk focuses on the third aspect and we will show examples of current work to establish an internationally recognized traceability chain for optical microscopy, reflectometry, scatterometry and ellipsometry at the micrometre and nanometre scale. To do this we need measurement institutes/companies that can provide high quality measurement, fabrication institutes/ companies that can manufacture high quality physical samples and a protocol for how each participant should measure and analyse the samples to obtain the required measurand and uncertainty. All the data will then be compared and checked for internal conformity and if available conformity with reference measurement from an established traceability chain.

The talk also will address measurement techniques such as optical microscopy, spectroscopic scatterometry, spectroscopic ellipsometry and reflectometry as well as data processing and the measurement uncertainty.





Authors (from 13 countries)

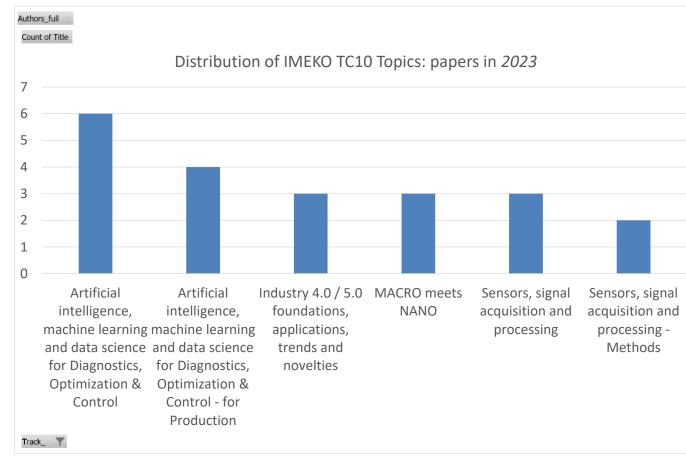




Key scientific topics - *2023* (21 published papers)

- T5 Artificial intelligence, machine learning and data science for Diagnostics, Optimization & Control
- T2 Sensors, signal acquisition and processing for Diagnostics, Optimization & Control
- T6 Industry 4.0 foundations, applications, trends and novelties
- MACRO meets NANO





- **→Increase impact**
- →Collaboration potential
- **→Follow others' results**





Past: 2 + 1 **Membership** candidate discussions

Present: 2 new members

Assignment for ALL: looking for new members

Name	Position	Country
Dr. Zsolt Janos Viharos	TC10 Chairperson	HUNGARY
Prof. Lorenzo Ciani	TC10 Vice Chairperson	ITALY
Dr. Piotr Bilski	TC10 Scientific Secretary	POLAND
Prof. Álvaro Silva Ribeiro		PORTUGAL
Prof. Marcantonio Catelani	Honorary member	ITALY
Prof. Laszlo Monostori		HUNGARY
Prof. Artur Lopes Ribeiro		PORTUGAL
Yakov Ben-Haim		ISRAEL
Prof. Eduard Egusquiza		SPAIN
Prof. B. K. N. Rao		UNITED KINGDOM
Prof. He Zhengjia		CHINA
Prof. Romauld Zielonko		POLAND
Dr. Eng. Yukio Hiranaka		JAPAN
Dr. Justinas Janulevicius		LITHUANIA
<u>Dr. Lauryna Siaudinyte</u>		NETHERLANDS
Prof. Helena Geirinhas Ramos		PORTUGAL
Dr. Oleg Bushuev		RUSSIA
Prof. Ephraim Suhir		USA
Prof. Diego Galar		SWEDEN
Dr. Oleksandr I. Shevchenko		UKRAINE
Mr Balázs Scherer		HUNGARY
Prof. Giulio D'Emilia		ITALY
Prof. Dr. Ing. David Delaux		FRANCE
Dr. Marco Carratú		ITALY
Dr. Gábor Nick		HUNGARY
Gabriele Patrizi		ITALY
Prof. Chao-Ching Ho		TAIWAN
Ádám Szaller		HUNGARY







Navigation Committees

Home General Chairs

Invited Keynote

Lecturers

Contacts

<u>Deadlines</u> **Dr. Zsolt János Viharos**

Committees

Committees

Authors

Chairperson of the IMEKO TC10 on Measurement for Diagnostics, Optimization and Control President of the Hungarian National IMEKO Committee (Member Organisation, MO)
Institute for Computer Science and Control (SZTAKI), Center of Excellence in Production
Informatics and Control, Eötvös Lóránd Research Network (ELKH), Center of Excellence of the

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Research Laboratory on Engineering and Management Intelligence

viharos.zsolt@sztaki.hu

Programme Prof. Lorenzo Ciani

Venue Vice Chairperson of the IMEKO TC10 on Measurement for Diagnostics, Optimization and

Control

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School of Engineering

Accommodation DINFO - Department of Information Engineering

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Sponsorship
Prof. Piotr Bilski

Photos Scientific Secretary of the IMEKO TC10 on Measurement for Diagnostics, Optimization and

Control

<u>Privacy Policy</u> Warsaw University of Technology

Faculty of Electronics and Information Technology

Institute of Radioelectronics

Politechniki 1 Warsaw 00-661 POLAND

piotr.bilski@pw.edu.pl

Prof. Eduard Egusquiza

International, Technical Programme Committee Members

(Invited, Member of IMEKO TC10)

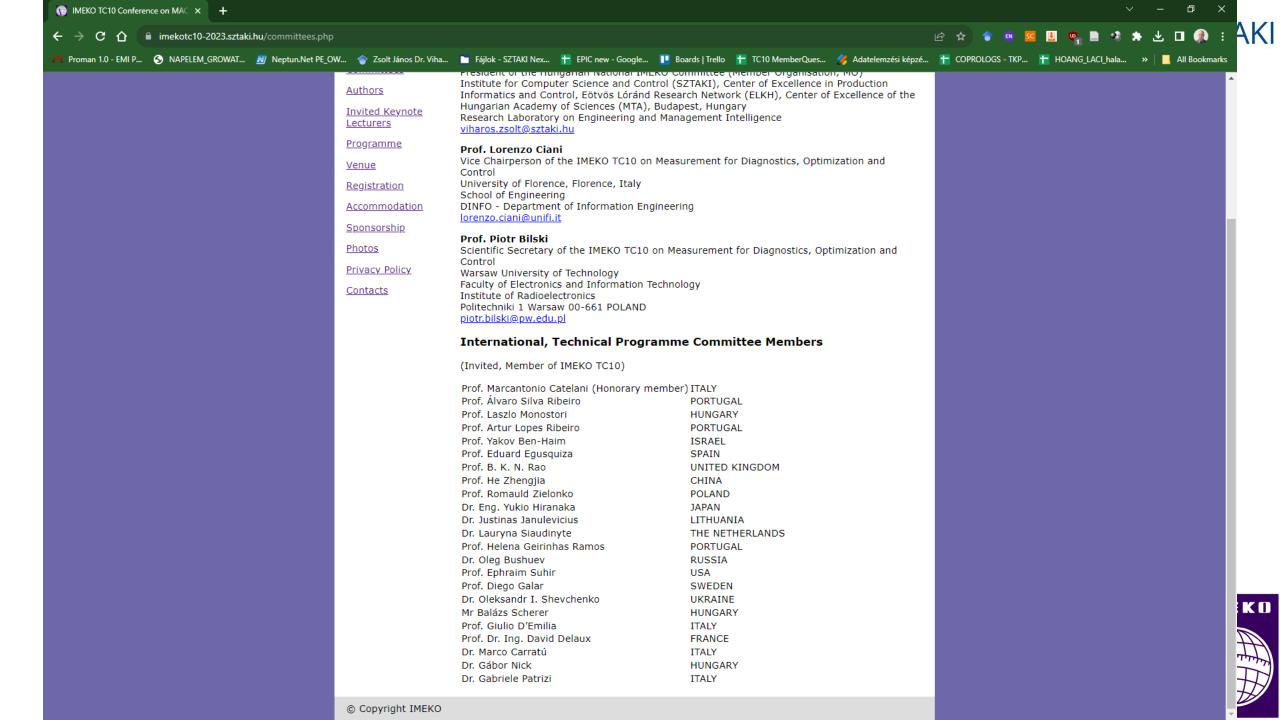
Prof. Marcantonio Catelani (Honorary member) ITALY
Prof. Álvaro Silva Ribeiro PORTUGAL
Prof. Laszlo Monostori HUNGARY
Prof. Artur Lopes Ribeiro PORTUGAL
Prof. Yakov Ben-Haim ISRAEL

Prof. B. K. N. Rao UNITED KINGDOM

SPAIN

Prof. He Zhengjia CHINA
Prof. Romauld Zielonko POLAND
Dr. Eng. Yukio Hiranaka JAPAN
Dr. Justinas Janulevicius LITHUANIA
Dr. Lauryna Siaudinyte THE NETHERLANDS







Thank you for the excellent operative organization!







- 40+ calls
- 50+ messages

• 20+ online meetings

• 150+ emails



Judit Stefkó Congress Ltd.



Proman 1.0 - EMI P... 🐧 NAPELEM GROWAT... 🐰 Neptun.Net PE OW... 🍲 Zsolt János Dr. Viha... 🖿 Fájlok - SZTAKI Nex... 🕇 EPIC new - Google... 📭 Boards | Trello 🔭 TC10 MemberQues... 🧳 Adatelemzési képzé...



Outcomes

1. Proceedings of the conference

IMEKO TC10 Conference on MAC x +

 NOT Open Access

2. Proceedings on the IMEKO website

- Open Access
- With DOI!
- Indexed in many databases

3. Special issue(s)

- Case-based
- Full review risky

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Conference on MACRO meets NANO in Measurement for Diagnostics, Optimization and Control

Delft, The Netherlands on September 21-22, 2023

INVITATION

The International Measurement Confederation IMEKO, Technical Committee 10 on Measurement for Diagnostics, Optimization and Control (https://www.imeko.org/index.php/tc10-homepage) kindly invites you to attend the 19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control" to be held in Delft, The Netherlands on September 21-22, 2023.

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CALL FOR PAPERS

Authors are kindly invited to submit extended abstracts in the appointed scientific topics, three to four pages long in A4 format. The abstract should report original research results of theoretical or applied nature and should explain the significance of the contribution to the research field. The abstracts will be reviewed by the International Programme Committee. Electronic abstracts must be in Adobe Acrobat (pdf) and should be sent according to the procedure described on https://www.imekotc10-2023.sztaki.hu/. Proceedings identifier: ISBN: 978-92-990090-4-8.

SPECIAL ISSUE

Selected papers of the conference will be invited to the Measurement, Mesurement Sensors and Acta IMEKO Special Issues. All submitted papers will undergo a regular peer review process. The manuscript MUST be significantly extended beyond the IMEKO TC10 conference paper.

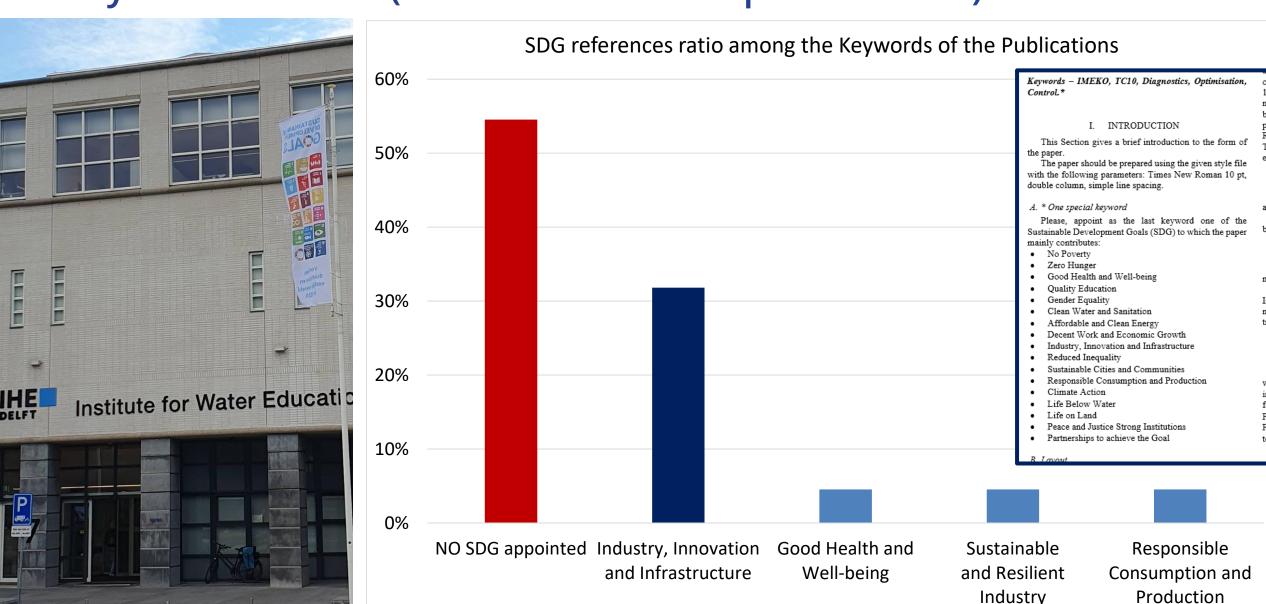
SCIENTIFIC TOPICS

- Basic principles and development trends in Measurement for Diagnostics, Optimization & Control
- · Sensors, signal acquisition and processing
- Failure & fault detection and prognosis
- Artificial intelligence, machine learning and data science for Diagnostics, Optimization & Control
- Industry 4.0 / 5.0 foundations, applications, trends and novelties.





Keywords vs. SDG (Sustainable Development Goals)









2023.09.21 Thursday

Hotel Arsenaal, Delft (Korte Geer 1, Delft)

9:00 - 9:30	REGISTRATION - Hotel Arsenaal
9:30 - 10:00	Welcome, Conference Openning - Hotel Arsenaal
10:00 - 10:45	Invited Key Lecturer: Dr. Richard Quintanilha Optical System Engineer Corporate Research & Technology; Carl Zeiss AG Carl ZEISS and Metrologies
10:45 - 11:00	COFFEE BREAK - Hotel Arsenaal
Scientific session	Session chair: Dr. Zsolt János Viharos - Artificial intelligence, machine learning and data science for Diagnostics, Optimization & Control - for Production
11:00 - 11:20	Chao-Ching Ho, Chun-Han Liu, Ming-Chieh Kao: Multi-task Learning Based on Deep Convolutional Neural Networks for Surface Defect Detection of Metal Gaskets
11:20 - 11:40	Dennis Grunert, Hellmich, Jan Hendrik, Henrik Heymann, Maik Frye, Robert H Schmitt: Machine Learning Management Model for Production
11:40 - 12:00	Eszter Kocsis, Attila Lukács, István Szalai: Investigation of atmospheric pressure plasma treatment on PCB surface finishes
12:00 - 12:20	Leonhard Czarnetzki, David Karnok, Viola Gallina, Johannes Breitschopf, Gashi Milot, Matthias Karner, Catherine Laflamme: Improving the Planning Quality in Practice with Artificial Intelligence
12:20 - 13:20	LUNCH - Hotel Arsenaal

Scientific session	Session chair: Prof. Lorenzo Ciani - Artificial intelligence, machine learning and data science for Diagnostics, Optimization & Control
13:20 - 13:40	Marco Carratù, Vincenzo Gallo, Antonio Pietrosanto, Gabriele Patrizi, Alessandro Bartolini, Lorenzo Ciani, Marcantonio Catelani: A deep learning method for current anomaly detection
13:40 - 14:00	Bartosz Połok, Piotr Bilski: Analysis of the Faults in Ratchet Mechanisms in the Presence of Noise
14:00 - 14:20	Roland Nagy, István Szalai: Development of machine learning assisted suspension vibration data-based road quality classification system
14:20 - 14:40	Yuko Hiranaka, Hidenori Katsumura, Koichi Tsujino, Masashi Nakagawa: Anomaly Score for Multiple Operating Modes of Rotating Machines by Using Conditional Variational Auto-Encoder
14:40 - 15:00	Marco Carratù, Vincenzo Gallo, Valter Laino, Consolatina Liguori: Use of Artificial Intelligence in optical microscope imaging
15:00 - 15:20	Alexander Shestakov, Dmitry Galyshev, Olga Ibryaeva, Victoria Eremeeva, Vladimir Sinitsin: Detection of Broken Bar Fault in Induction Motor Using Higher-Order Harmonics Analysis
15:20 - 15:50	COFFEE BREAK - Hotel Arsenaal
15:50 - 17:00	All Participants - IMEKO TC10 Meeting
19:00 -	Gala Dinner in <u>Delfts Brouwhuis</u> Hippolytusbuurt 43; 2611HM Delft; 06-43255788





_TC IU



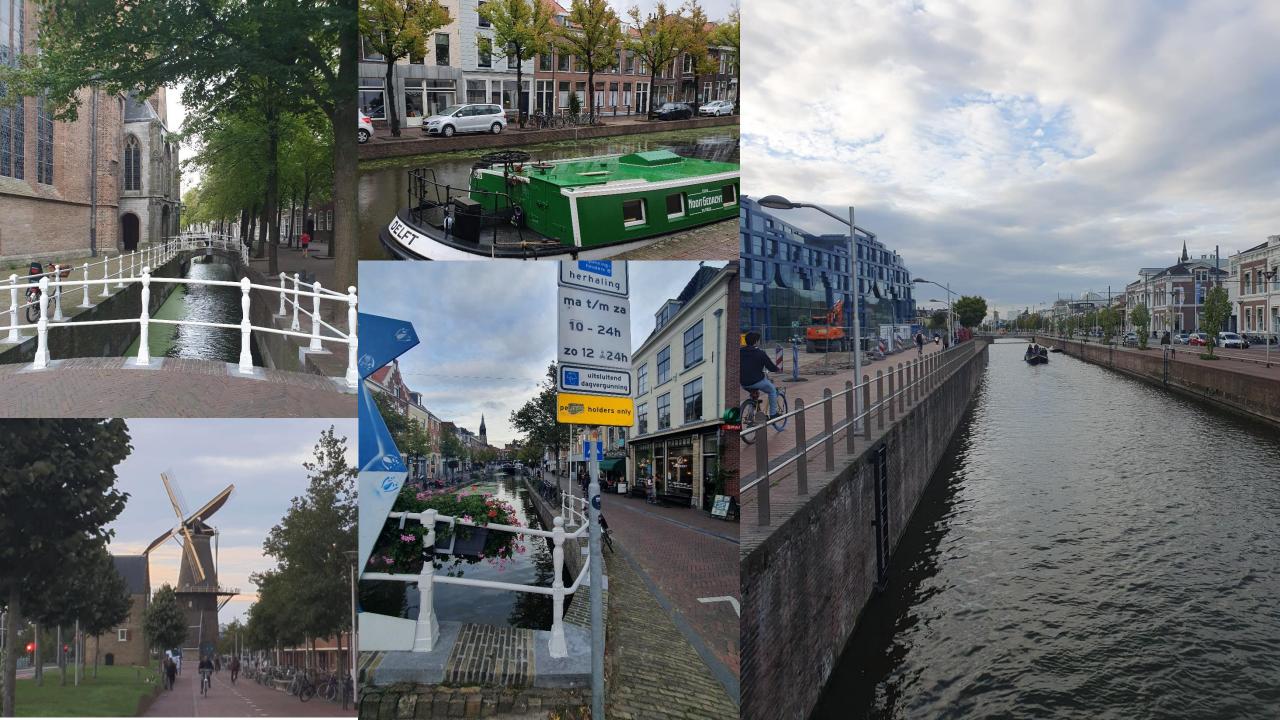
2023.09.22 Friday

Hotel Arsenaal, Delft (Korte Geer 1, Delft)

Scientific session	Session chair: Prof. Piotr Bilski - Sensors, signal acquisition and processing	
9:00 - 9:20	Gabriele Patrizi, Marco Carratù, Lorenzo Ciani, Paolo Sommella, Roberto Singuaroli, Marcantonio Catelani, Antonio Pietrosanto: Dynamic characterization of MEMS-based Inertial Unit under combined vibration stresses	
9:20 - 9:40	Zsolt Tóth, Eszter Kocsis, Attila Lukács, István Szalai: No-clean flux residues detection with impedance measurements	
9:40 - 10:00	Giulio D'Emilia, Luciano Chiominto, Antonella Gaspari, Emanuela Natale, Andrea Prato, Alessandro Schiavi: A contribution to trustworthiness of data from digital MEMS accelerometers for smart mobility	
10:00 - 10:20	Raissa Schiavoni, Antonio Masciullo, Andrea Cataldo: Skin monitoring and diagnostics: towards a wearable low-cost system	
10:20 - 10:40	Alexander Shestakov, Olga Ibryaeva, Victoria Eremeeva, Vladimir Sinitsin: The Detection of Rotor Bar Faults in Induction Motors Using the Recursive Matrix Pencil Method	
10:40 - 11:10	COFFEE BREAK - Hotel Arsenaal	
Scientific session	Session chair: Prof. Giulio D'Emilia - Industry 4.0 / 5.0 foundations, applications, trends and novelties	
11:10 - 11:30	Botond Kádár, Eduardo Colangelo, Gábor Nick, László Fükő, Ádám Szaller: Flexible Manufacturing Concept at Bosch: A low-cost implementation of an Industry 4.0 concept	
11:30 - 11:50	Ferenc Kása, Péter Wolf, Tamás Gyulai, Zsolt János Viharos: Learning Factories towards Industry 5.0: Evolutionary or Revolutionary?	
11:50 - 12:10	Marc Vila Forteza, Ajit Kumar Verma, Diego Galar Pascual, Uday Kumar: RELIABILITY PREDICTION OF CENTRIFUGAL PUMPS IN DIGITIZED OIL & GAS ENVIRONMENT	
12:10 - 13:00	LUNCH - Hotel Arsenaal	

13:00 - 13:40	Invited Key Lecturer: Poul Erik Hansen Principal scientist Danich National Metrology Institute Traceability and uncertainty in optical measurements
Scientific session	Session chair: Dr. Lauryna Siaudinyté: MACRO meets NANO
13:40 - 14:00	Atul Tiwari, Sebastian Heidenreich, Victor Soltwisch: Bayesian approach for determining the optical constants of layered systems using EUV reflectometry: The effect of different priors
14:00 - 14:20	Poul-Erik Hansen, Lauryna Siaudinyte, Thomas Siefke: In situ calibration of numerical aperture effects in optical microscopes
14:20 - 14:40	Thomas Siefke, Astrid Tranum Rømer, Lauryna Siaudinyté, Poul-Erik Hansen: Fine details of structural deviations in reference samples for scatterometry
14:40 - 15:10	COFFEE BREAK - Hotel Arsenaal
15:10 - 16:00	Closing and Award Ceremony - Hotel Arsenaal









THE ROOM FOR OUR TC10 Conference is the Blue Room:



DREAM OF ADVENTURES UNDER THE HISTORIC BEAMED CEILING

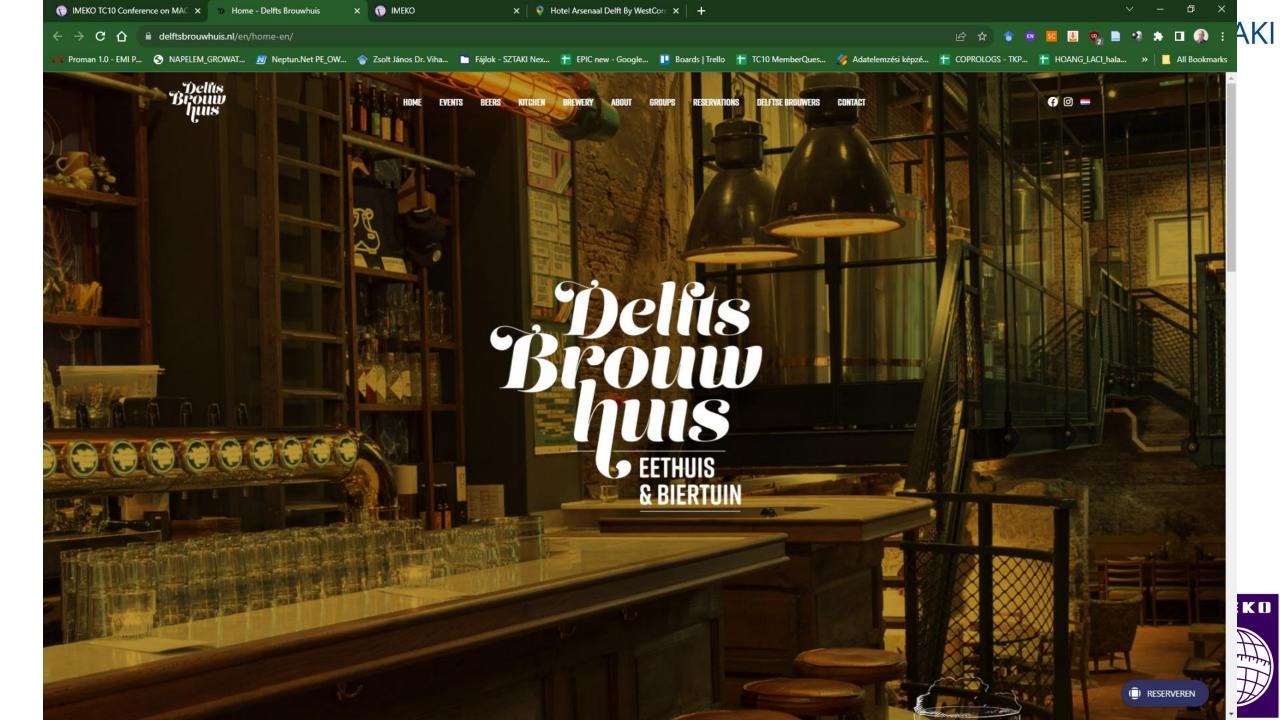
Hotel Arsenaal Delft offers 63 hotel rooms, including two suites, superior rooms and comfort rooms. Every room breathes authenticity, reminding us of the rich history of the city of Delft. Thanks to the sixteenth century construction, all rooms have an authentic, unique and romantic character. The beds and facilities are similar in all rooms, but may vary in size and view. Hotel Arsenaal is a non-smoking hotel. It is therefore not allowed to smoke in the rooms.



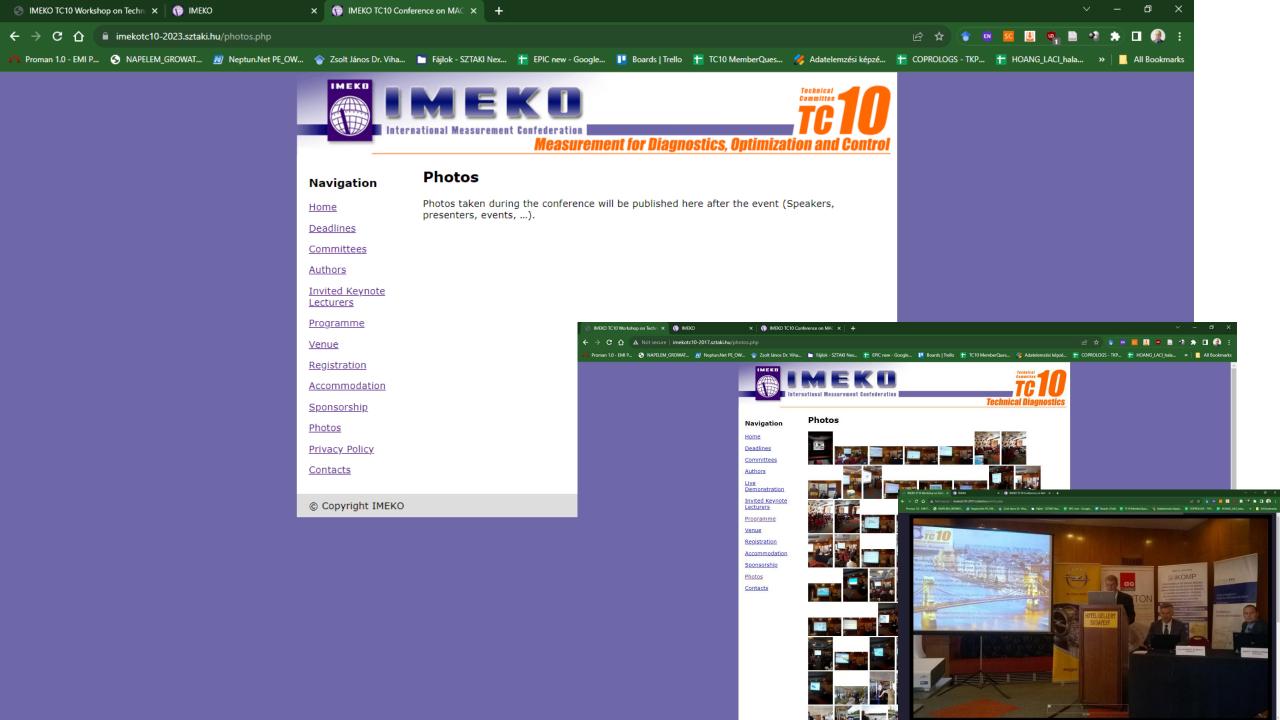
2023.09.21, Delft, The Netherlands, IMEKO TC10 Meeting













Workshop awards

 An award will be given for the Best Scientific Paper & Presentation of the Conference.

- An award will be given for the Best Scientific Paper & Presentation by a Woman on the Conference.
- To encourage the attendance of young researchers, an award will be given for the Best Paper Authored and Presented by a Young Researcher.





International Measurement Confederation

Certificate of Award for the Best Scientific Paper & Presentation Presented by a Woman

In recognition of professional excellence, the paper titled

Investigation of atmospheric pressure plasma treatment on PCB surface finishes

presented at the

19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control" to be held in Delft, The Netherlands on September 21-22, 2023.

The author(s) of this paper,

Eszter Kocsis, Attila Lukács, István Szalai

are hereby congratulated and recognised for the excellent research work reported in the paper and presentation.

Dr. Zsolt János Viharos Chairperson of IMEKO TC10 on Measurement for Diagnostics, Optimization and Control

International Measurement Confederation



Certificate of Award for the Best Scientific Paper & Presentation Presented by a Young Scientists

In recognition of professional excellence, the paper titled

Dynamic characterization of MEMS-based Inertial Unit under combined vibration stresses

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19th IMEKO TC10 Conference: "MACRO meets NANO in Measurement for Diagnostics, Optimization and Control" to be held in Delft, The Netherlands on September 21-22, 2023.

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International Measurement Confederation



Certificate of Award for the Best Scientific Paper & Presentation

In recognition of professional excellence, the paper titled

Multi-task Learning Based on Deep Convolutional Neural Networks for Surface Defect Detection of Metal Gaskets

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Chao-Ching Ho, Chun-Han Liu, Ming-Fu Chen, Ming-Chieh Kao

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Dr. Zsolt János Viharos Chairperson of IMEKO TC10 on Measurement for Diagnostics, Optimization and Control



Key, actual challenges

- On TC level
 - Internationalization
 - 41 IMEKO member "country" vs. 8-10 "TC10 active member country"
 - The TC10 topic is everywhere → finding the active, motivated people in additional IMEKO countries
 - Missing: Albania, Austria, Belgium, Bosnia and Herzegovina, Brazil, Bulgaria, Canada, China, Congo, Croatia, Czech Republic, Finland, Germany, Greece, India, Kazakhstan, Kenya, Korea, Romania, Rwanda, Russia, Serbia, Slovakia, Slovenia, South Afrika, Spain, Switzerland, Thailand, Türkiye, Uganda, Ukraine, United Arab Emirates, United Kingdom, USA
 - BUT: The Netherlands...Taiwan...
 - Finding successors for *Inactive members*
 - How to share the work among TC10 leaders
 - Conference host country: having more papers/participants by the host
 - Various difficulties with the new conferencing system (support needed)
 - Lack of joint scientific projects
- On IMEKO level
 - TC Functioning WG to continue^{13/06/2023}



As the Chairman of the IMEKO XXIV World Congress it is a great honor and privilege to welcome you to Hamburg, cosmopolitan city in the north of Germany.

Under the headline **Think Metrology**, we will shed light on both well-established and new, highly current topics such as digitalization.

Hamburg has been a gateway from Germany and Europe to the rest of the world for over 1400 years. Over the centuries, trade and innovation have been instrumental in the growth and development of the city, now the second largest in Germany. This and over 20,000 researchers and university students at numerous









Enjoy our IMEKO TC10 conference 2023 Enjoy the scientific life inside our IMEKO TC10 on Measurement for Diagnostics, Optimization and Control



Dr. Zsolt János Viharos

Senior research fellow, Institute for Computer Science and Control

Vice Dean for Science of the John von Neumann University

President of the Hungarian Member Organisation of IMEKO

Chairperson, IMEKO TC10 on Measurement for Diagnostics, Optimization and Control

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Seeing beyond

